

MProbe® MSP

Microscope Thin Film Measurement System

It is easy to be an expert with MProbe

Majority of translucent or lightly absorbing films can be measured quickly and reliably:Oxides,Nitrides, Photoresists, Polymers, Semiconductors (Si, aSi, polySi), Compound Semiconductors (AlGaAs, InGaAs, CdTe,CIGS),Hard coatings (SiC, DLC), Polymer coatings (Paralene, PMMA, Polyamides), adhesives, thin metal films and many more.

Thickness Range: 1 nm - 1.8 mm Wavelength Range: 200nm -1700nm Spot size: 200µm to 2 µm

Thin -Film solar cells: aSi, TCO, CIGS, CdS, CdTe,perovskytes - full solar stack measurement. LCD, FPD application: ITO, Cell Gaps, Polyamides. Optical Coatings: dielectric filters, hardness coating, antireflection coating. Semiconductor and dielectics: Oxides, Nitrides, OLED stack.

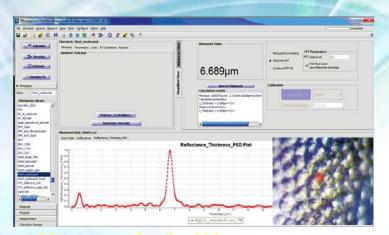
Biomedical: stents, orthopedic implants coating

Extensive materials library (500+ materials) - new materials easily added. Support of parameterized materials: Cauchy, Tauc-Lorentz, Cody-Lorentz, EMA and many more....

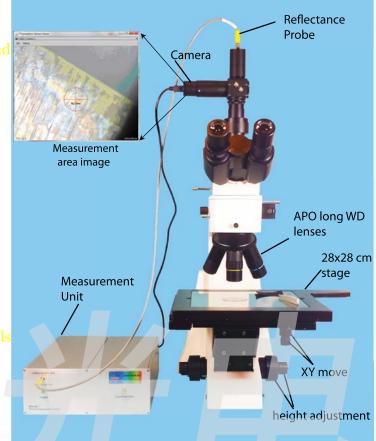
Flexible: Easy integration with external softwares.

Measurement parameters: thickness, optical constants, surface roughness. Unlimited number of layers.

Ease of use and powerful analysis tools -ready for R&D and production application. One-click measurement and analysis. Simulation & sensitivity, background and scaling correction, linked layers and materials, multisample measurements, dynamic measurement and production batch processing.



Measurement of coating thickness on stent



- Integrated camera and software to exactly pinpoint measurement location and display results on the image
- 280x280mm (11'x11") sample stage
- Height adjustment up to 30 mm
- Long working distance (WD) lenses (20mm - 35mm)
- Achromatic IIV-NIR tube lens

Clean room class 1000 design

Basic Options/ Specification

-MXY[6 or 8]	Motorized XY stage 6" x6" (150mm) or 8"x8" (200mm). Controller and software support for mapping is included. 0.5 μm step size, +-1 μm repeatability	11"x 11" manual stage is included as standard with all models
-TOM [VISNIR/ UV]	Transmittance measurement configuration. Includes: insert for stage, condenser, fiber optics (TO).	for UV, VisIR and UV- VISNIR models
APO VIS objectives	Following APO, 95mm parfocal objectives for visible range(400-1000 nm) are available: 10x, 20x, 50x, 100X	
APO VisNIR objectives	Following APO, 95mm parfocal objectives for visible range(400-1700 nm) are available: 10x, 20x, 50x	
UV-NIR objectives	All-reflective achromatic objective (200-2000nm wavelengh range), 95mm parfocal are available: 10x, 15x (long working distance 24mm to 31 mm)	6x is included as stan- dard

Model	Wavelength range	Spectrometer/Detector/Light source	Thickness range*
VIS-MSP	400-1000 nm	Spectrometer F4/Si 3600 pixels/ Tungsten - Halogen light source	10 nm to 75 μm
UVVisSR-MSP	200-1000 nm	Spectrometer F4/ Si CCD 2048 pixels/ Deuterium & Tungsten-Halogen source	1 nm to 75 μm
UVVisF-MSP	200 - 900nm	Spectrometer F4/ Si CCD 2048 pixels 20W Xe fl ush lamp	
		Spectrometer F4 Si CCD 3600 pixels(Vis channel);Spectrometer F4/512 InGaAs PDA(NIR channel) Tungsten-Halogen light source	
UVVISNIR- MSP	200 -1700 nm	Spectrometer F4 Si CCD 2048 pixels(UVVis channel);Spectrometer F4/512 InGaA (NIR channel) Deuterium & Tungsten-Halogen light source	
NIRHR-MSP		Spectrometer F4/512 pixels InGaAs/ 20W SLD light source +50W TH lamp	10 μm-1800 μm(quartz) 4 μm -500 μm(Si)

Measurement principle: Optical spectroscopic reflectometer (transmittance measurement is available as an option) Other configuration are available. One year limited warranty on labor and materials for all system.

上海昊量光电设备有限公司

电话: 4006-888-532

邮箱: info@auniontech.com

官网: www.auniontech.com

中国区代理 上海昊量光电设备有限公司 Phone: 4006-888-532 地址h上海市徐近区虹梅路2007/号6号楼3楼com E-mail: info@auniontech.com